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Low r<sub>DS(on)</sub> . . . 0.23 Ω Typ
 High Voltage Output . . . 60 V

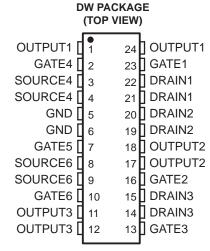
Extended ESD Capability . . . 4000 V

• Pulsed Current . . . 11.25 A Per Channel

Fast Commutation Speed

#### description

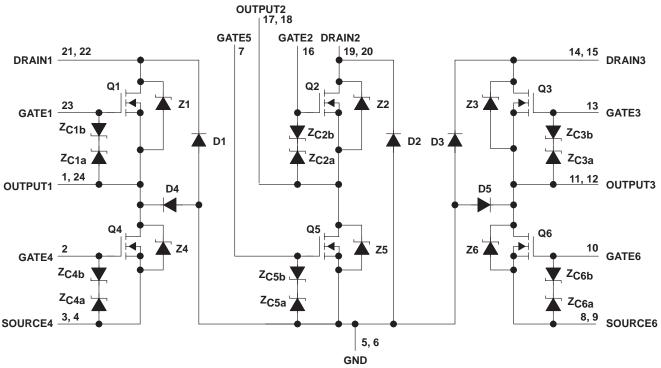
The TPIC1301 is a monolithic gate-protected power DMOS array that consists of six electrically isolated N-channel enhancement-mode DMOS transistors configured as three half H-bridges. Each transistor features integrated high-current zener diodes (Z<sub>CXa</sub> and Z<sub>CXb</sub>) to prevent gate damage in the event that an overstress condition



occurs. These zener diodes also provide up to 4000 V of ESD protection when tested using the human-body model of a 100-pF capacitor in series with a 1.5-k $\Omega$  resistor.

The TPIC1301 is offered in a 24-pin wide-body surface-mount (DW) package and is characterized for operation over the case temperature range of  $-40^{\circ}$ C to  $125^{\circ}$ C.

#### schematic



NOTE: For correct operation, no terminal pin may be taken below GND.

## TPIC1301 3-HALF H-BRIDGE GATE-PROTECTED POWER DMOS ARRAY

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# absolute maximum ratings over operating case temperature range (unless otherwise noted)<sup>†</sup>

Drain-to-GND voltage, V <sub>DG</sub>	100 V
Drain-to-source voltage, V <sub>DS</sub>	60 V
Output-to-GND voltage	
SOURCE4, SOURCE6-to-GND voltage	60 V
Gate-to-source voltage range, V <sub>GS</sub>	–9 V to 18 V
Continuous drain current, each output, T <sub>C</sub> = 25°C	2.25 A
Continuous source-to-drain diode current, T <sub>C</sub> = 25°C	2.25 A
Pulsed drain current, each output, I <sub>max</sub> , T <sub>C</sub> = 25°C (see Note 1 and Figure 15)	11.25 A
Continuous gate-to-source zener-diode current, T <sub>C</sub> = 25°C	±50 mA
Pulsed gate-to-source zener-diode current, T <sub>C</sub> = 25°C	±500 mA
Single-pule avalanche energy, E <sub>AS</sub> , T <sub>C</sub> = 25°C (see Figures 4, 15, and 16)	17.2 mJ
Continuous total dissipation, T <sub>C</sub> = 25°C (see Figure 15)	1.39 W
Operating virtual junction temperature range, T <sub>J</sub>	. −40°C to 150°C
Operating case temperature range, T <sub>C</sub>	40°C to 125°C
Storage temperature range	. −65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	260°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: Pulse duration = 10 ms, duty cycle = 2%



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# electrical characteristics, $T_C = 25^{\circ}C$ (unless otherwise noted)

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
V <sub>(BR)DSX</sub>	Drain-to-source breakdown voltage	$I_D = 250 \mu\text{A},$	$V_{GS} = 0$	60			V
V <sub>GS(th)</sub>	Gate-to-source threshold voltage	I <sub>D</sub> = 1 mA, See Figure 5	$V_{DS} = V_{GS}$	1.5	1.75	2.2	V
V(BR)GS	Gate-to-source breakdown voltage	IGS = 250 μA		18			V
V(BR)SG	Source-to-gate breakdown voltage	I <sub>SG</sub> = 250 μA		9			V
V <sub>(BR)</sub>	Reverse drain-to-GND breakdown voltage (across D1 – D5)	Drain-to-GND curren	t = 250 μA	100			V
V <sub>DS(on)</sub>	Drain-to-source on-state voltage	I <sub>D</sub> = 2.25 A, See Notes 2 and 3	V <sub>GS</sub> = 10 V,		0.52	0.62	٧
V <sub>F(SD)</sub>	Forward on-state voltage, source-to-drain	I <sub>S</sub> = 2.25 A, V <sub>GS</sub> = 0 (Z1 – Z6), See Notes 2 and 3 ar	nd Figure 12		1	1.2	V
VF	Forward on-state voltage, GND-to-drain	I <sub>D</sub> = 2.25 A (D1 – D5) See Notes 2 and 3			5		V
	Drain current-gate shorted to source	V <sub>DS</sub> = 48 V,	T <sub>C</sub> = 25°C		0.05	1	^
IDSS	Drain current-gate shorted to source	$V_{GS} = 0$	T <sub>C</sub> = 125°C		0.5	10	μΑ
IGSSF	Forward-gate current, drain short circuited to source	V <sub>GS</sub> = 15 V,	V <sub>DS</sub> = 0		20	200	nA
IGSSR	Reverse-gate current, drain short circuited to source	V <sub>SG</sub> = 5 V,	V <sub>DS</sub> = 0		10	100	nA
	Leakage current, drain-to-GND	V 40.V	T <sub>C</sub> = 25°C		0.05	1	^
l <sub>lkg</sub>	Gate shorted to source	V <sub>DGND</sub> = 48 V	T <sub>C</sub> = 125°C		0.5	10	μΑ
race	Static drain-to-source on-state resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 2.25 A,	T <sub>C</sub> = 25°C		0.23	0.275	Ω
<sup>r</sup> DS(on)	Static drain-to-source on-state resistance	See Notes 2 and 3 and Figures 6 and 7	T <sub>C</sub> = 125°C		0.35	0.4	22
9fs	Forward transconductance	V <sub>DS</sub> = 15 V, See Notes 2 and 3 ar	I <sub>D</sub> = 1.125 A, nd Figure 9	1.6	2.21		S
C <sub>iss</sub>	Short-circuit input capacitance, common source				200	250	
C <sub>oss</sub>	Short-circuit output capacitance, common source	$V_{DS} = 25 \text{ V},$	V <sub>GS</sub> = 0,		175	220	pF
C <sub>rss</sub>	Short-circuit reverse transfer capacitance, common source	f = 1 MHz,	See Figure 11		40	75	Pi

NOTES: 2. Technique should limit T<sub>J</sub> – T<sub>C</sub> to 10°C maximum.

# source-to-drain and GND-to-drain diode characteristics, $T_{\hbox{\scriptsize C}}$ = 25 $^{\circ}\hbox{\scriptsize C}$

PARAMETER TEST CON					MIN	TYP	MAX	UNIT
t <sub>rr</sub>	Reverse-recovery time	Is = 1.125 A,	V <sub>DS</sub> = 48 V,	74 70 170		50		ns
Q <sub>RR</sub>	Total diode charge	VGS = 0, See Figures 1 and 14	di/dt = 100 A/μs,	Z1, Z2, and Z3		65		nC

<sup>3.</sup> These parameters are measured with voltage-sensing contacts separate from the current-carrying contacts.

## TPIC1301 3-HALF H-BRIDGE GATE-PROTECTED POWER DMOS ARRAY

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# resistive-load switching characteristics, $T_C = 25^{\circ}C$

	PARAMETER	TEST CONDITIONS			MIN	TYP	MAX	UNIT	
td(on)	Turn-on delay time					25	50		
td(off)	Turn-off delay time	$V_{DD} = 25 \text{ V},$ $t_{dis} = 10 \text{ ns},$		$R_L = 20 \Omega$ ,	$t_{en} = 10 \text{ ns},$		25	50	
t <sub>r</sub>	Rise time					See Figure 2	See Figure 2		15
tf	Fall time					7	15		
Qg	Total gate charge					6.2	7.4		
Q <sub>gs(th)</sub>	Threshold gate-to-source charge	-	V <sub>DS</sub> = 48 V, I <sub>D</sub> = 1.125 A, See Figure 3	$V_{GS} = 10 V$ ,		0.7	0.8	nC	
Q <sub>gd</sub>	Gate-to-drain charge	gar igaic c				2.4	2.9		
L <sub>D</sub>	Internal drain inductance					5		al I	
LS	Internal source inductance			•		5		nΗ	
Rg	Internal gate resistance					0.25		Ω	

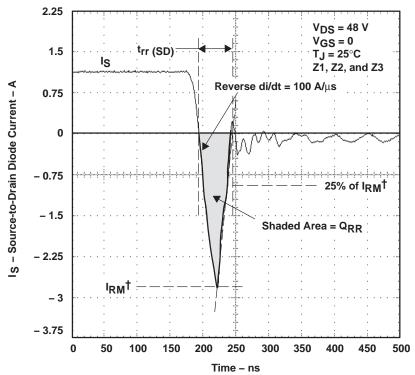
#### thermal resistance

PARAMETER		PARAMETER TEST CONDITIONS		TYP	MAX	UNIT
$R_{\theta JA}$	Junction-to-ambient thermal resistance	See Notes 4 and 7		90		°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	See Notes 5 and 7		45		°C/W
$R_{\theta JP}$	Junction-to-pin thermal resistance	See Notes 6 and 7		28		°C/W

NOTES: 4. Package mounted on an FR4 printed-circuit board with no heatsink.

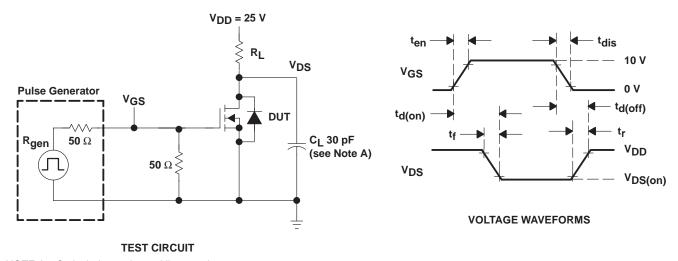
- 5. Package mounted on a 24 in<sup>2</sup>, 4-layer FR4 printed-circuit board.
- 6. Package mounted in intimate contact with infinite heatsink.
- 7. All outputs with equal power

#### PARAMETER MEASUREMENT INFORMATION



†I<sub>RM</sub> = maximum recovery current

Figure 1. Reverse-Recovery-Current Waveform of Source-to-Drain Diode



NOTE A: C<sub>L</sub> includes probe and jig capacitance.

Figure 2. Resistive-Switching Test Circuit and Voltage Waveforms



#### PARAMETER MEASUREMENT INFORMATION

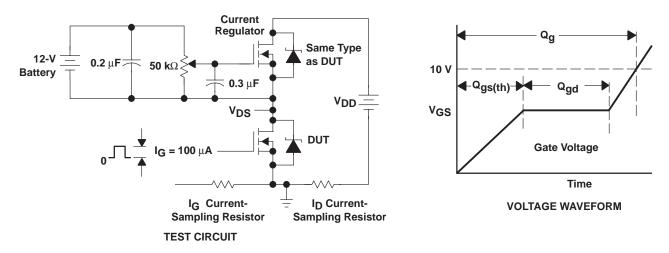
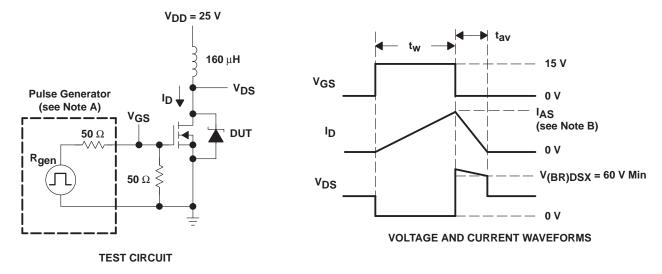


Figure 3. Gate-Charge Test Circuit and Voltage Waveform



NOTES: A. The pulse generator has the following characteristics:  $t_r \le 10$  ns,  $t_f \le 10$  ns,  $Z_O = 50 \Omega$ .

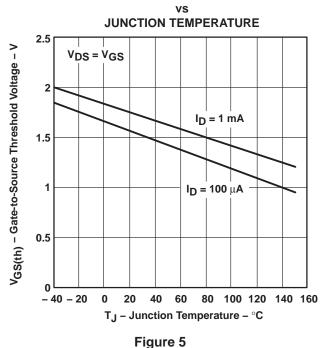
B. Input pulse duration  $(t_W)$  is increased until peak current IAS = 11.25 A.

Energy test level is defined as  $E_{AS} = \frac{I_{AS} \times V_{(BR)DSX} \times t_{av}}{2} = 17.2 \text{ mJ}.$ 

Figure 4. Single-Pulse Avalanche Energy Test Circuit and Waveforms

#### TYPICAL CHARACTERISTICS

#### **GATE-TO-SOURCE THRESHOLD VOLTAGE**



### STATIC DRAIN-TO-SOURCE ON-STATE RESISTANCE

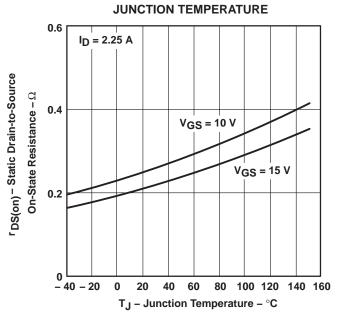
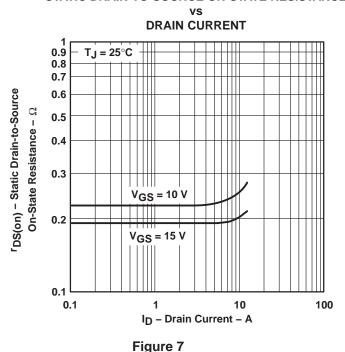


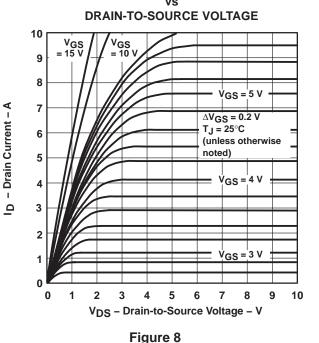
Figure 6

#### i igui e 3

#### STATIC DRAIN-TO-SOURCE ON-STATE RESISTANCE



# DRAIN CURRENT





#### **TYPICAL CHARACTERISTICS**

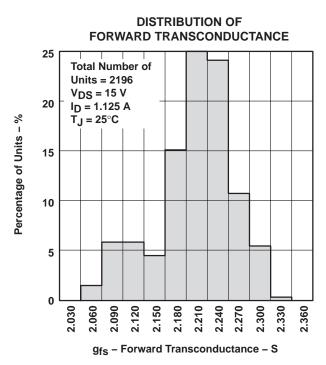
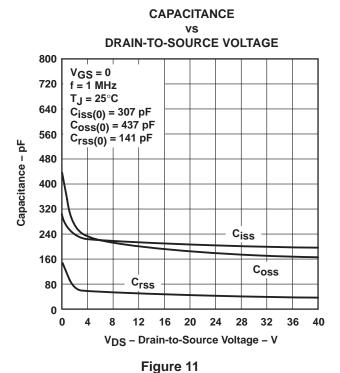


Figure 9



**DRAIN CURRENT** vs **GATE-TO-SOURCE VOLTAGE** 

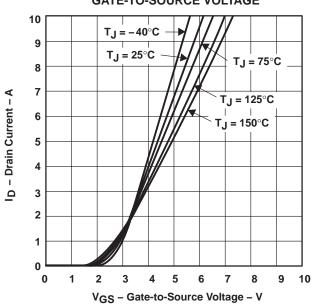


Figure 10

# **SOURCE-TO-DRAIN DIODE CURRENT SOURCE-TO-DRAIN VOLTAGE**

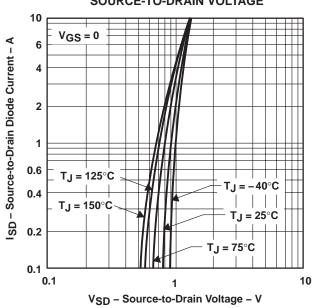


Figure 12

#### TYPICAL CHARACTERISTICS

# DRAIN-TO-SOURCE VOLTAGE AND GATE-TO-SOURCE VOLTAGE

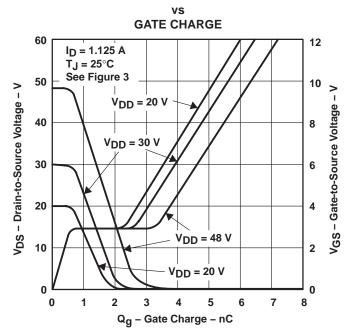


Figure 13

#### REVERSE RECOVERY TIME

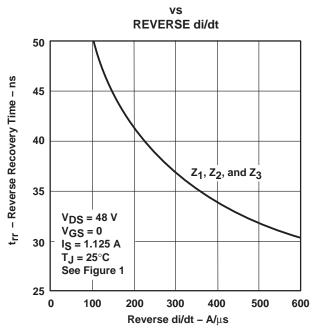
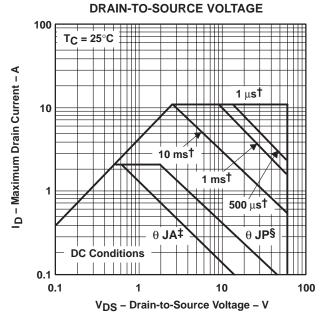


Figure 14

#### THERMAL INFORMATION

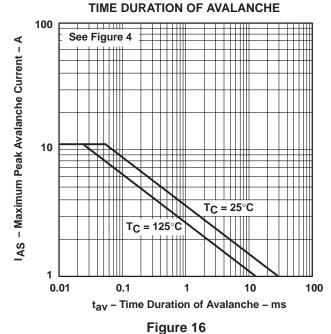
# MAXIMUM DRAIN CURRENT vs



<sup>†</sup>Less than 2% duty cycle

Figure 15

# MAXIMUM PEAK AVALANCHE CURRENT vs



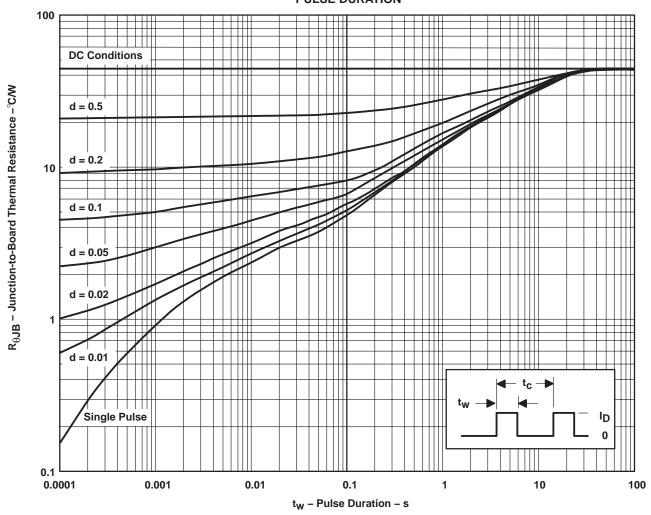


<sup>‡</sup> Device mounted on FR4 printed-circuit board with no heatsink.

<sup>§</sup> Device mounted in intimate contact with infinite heatsink.

#### THERMAL INFORMATION

# DW PACKAGE<sup>†</sup> JUNCTION-TO-BOARD THERMAL RESISTANCE vs PULSE DURATION



† Device mounted on 24 in<sup>2</sup>, 4-layer FR4 printed-circuit board with no heatsink

NOTE A.  $Z_{\theta B}(t) = r(t) R_{\theta JB}$   $t_W = \text{pulse duration}$   $t_C = \text{cycle time}$  $d = \text{duty cycle} = t_W/t_C$ 

Figure 17



#### PACKAGE OPTION ADDENDUM

8-Apr-2005

#### **PACKAGING INFORMATION**

Orderable Device	Status <sup>(1)</sup>	Package Type	Package Drawing	Pins Package Qty	Eco Plan <sup>(2)</sup>	Lead/Ball Finish	MSL Peak Temp (3)
TPIC1301DW	OBSOLETE	SOIC	DW	24	TBD	Call TI	Call TI

<sup>(1)</sup> The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

**NRND:** Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS) or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

**Pb-Free** (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

(3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

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DW (R-PDSO-G24)

## PLASTIC SMALL OUTLINE



NOTES: A. All linear dimensions are in inches (millimeters). Dimensioning and tolerancing per ASME Y14.5M-1994.

- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).
- D. Falls within JEDEC MS-013 variation AD.



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